

**Notice of References Cited**

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Applicant(s)/Patent Under  
Reexamination  
FRANK, MICHAEL L.

Examiner

Khai M. Nguyen

Art Unit

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,697,088	12-1997	Gu, Wang-Chang Albert	455/307
	B	US-4,302,739	11-1981	Hallford, Ben R.	333/204
	C	US-5,475,346	12-1995	Mullett, Anthony J.	333/25
	D	US-5,825,263	10-1998	Falt, Christopher Edgar	333/204
	E	US-5,949,299	09-1999	Harada, Nobumi	333/25
	F	US-4,667,173	05-1987	Okochi, Sadao	333/177
	G	US-6542055	04-2003	Frank et al.	333/133
*	H	US-US 2003/0020568 A ✓	01-2003	Mizutani et al.	333/26
*	I	US-2002/0175002 A ✓	11-2002	Sakakura et al.	174/255
*	J	US-2002/0171508 A ✓	11-2002	Harada et al.	333/133
*	K	US-US 2003/0025571 A ✓	02-2003	Maekawa et al.	333/26
*	L	US-5,705,960	01-1998	Izumiyama, Toru	333/26
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB 2 243 038 A	10-1991	United Kingdom	Richard John Swain	H03H 7/42
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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